



# SLOVENSKI STANDARD

## SIST EN 61830:2002

01-september-2002

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### Microwave ferrite components - Measuring methods for major properties (IEC 61830:1997)

Microwave ferrite components - Measuring methods for major properties

Mikrowellenferritbauelemente - Meßverfahren für die Hauptmikrowelleneigenschaften

Composants ferrites pour hyperfréquences - Méthodes de mesure des principales propriétés

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Ta slovenski standard je istoveten z: ~~SIST EN 61830:2002~~ EN 61830:1998

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#### ICS:

29.100.10	Magnetne komponente	Magnetic components
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**SIST EN 61830:2002**

**en**

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EUROPEAN STANDARD  
NORME EUROPÉENNE  
EUROPÄISCHE NORM

**EN 61830**

February 1998

ICS 29.100.10

Descriptors: Microwave ferrite components, major microwave properties, measuring methods, return loss, forward loss, reverse loss, phase-shift, group-delay

English version

**Microwave ferrite components  
Measuring methods for major properties  
(IEC 61830:1997)**

Composants ferrites pour  
hyperfréquences  
Méthodes de mesure  
des principales propriétés  
(CEI 61830:1997)

Mikrowellenferritbauelemente  
Meßverfahren für die  
Hauptmikrowelleneigenschaften  
(IEC 61830:1997)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

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CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

### Foreword

The text of document 51/486/FDIS, future edition 1 of IEC 61830, prepared by IEC TC 51, Magnetic components and ferrite materials, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61830 on 1998-01-01.

The following dates were fixed:

- latest date by which the EN has to be implemented  
at national level by publication of an identical  
national standard or by endorsement (dop) 1998-10-01
- latest date by which the national standards conflicting  
with the EN have to be withdrawn (dow) 1998-10-01

Annexes designated "normative" are part of the body of the standard.  
In this standard, annex ZA is normative.  
Annex ZA has been added by CENELEC.

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### Endorsement notice

The text of the International Standard IEC 61830:1997 was approved by CENELEC as a European Standard without any modification.

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**Annex ZA** (normative)**Normative references to international publications  
with their corresponding European publications**

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE: When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60510-1-3 + A1	1980 1988	Methods of measurement for radio equipment used in satellite earth stations Part 1: Measurements common to sub-systems and combinations of sub-systems Section Three: Measurements in the i.f. range	-	-

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# NORME INTERNATIONALE INTERNATIONAL STANDARD

**CEI  
IEC**

**61830**

Première édition  
First edition  
1997-11

## Composants ferrites pour hyperfréquences – Méthodes de mesure des principales propriétés

## Microwave ferrite components – Measuring methods for major properties (standards.iteh.ai)

SIST EN 61830:2002

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International Electrotechnical Commission  
Telefax: +41 22 919 0300

3, rue de Varembé Geneva, Switzerland  
e-mail: [inmail@iec.ch](mailto:inmail@iec.ch) IEC web site <http://www.iec.ch>



Commission Electrotechnique Internationale  
International Electrotechnical Commission  
Международная Электротехническая Комиссия

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PRICE CODE

**M**

Pour prix, voir catalogue en vigueur  
For price, see current catalogue

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

# **MICROWAVE FERRITE COMPONENTS – MEASURING METHODS FOR MAJOR PROPERTIES**

## FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61830 has been prepared by IEC technical committee 51: Magnetic components and ferrite materials.

The text of this standard is based on the following documents:

FDIS	Report on voting
51/486/FDIS	51/494/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.